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CLAIMS

1. A nitride semiconductor light emitting device comprising:

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a plurality of nitride semiconductor layers having an active layer that generates light through recombination of electrons and holes; and

an electrode layer disposed on the plurality of the nitride semiconductor layers, the electrode layer being electrically in contact with the plurality of the nitride semiconductor layers,

wherein the plurality of the nitride semiconductor layers include a p-type nitride semiconductor layer formed using ammonia together with hydrazine-based material as nitrogen precursor.

2. A nitride semiconductor light emitting device comprising:

a plurality of nitride semiconductor layers having an active layer that
generates light through recombination of electrons and holes;

an electrode layer disposed on the plurality of the nitride semiconductor layers, the electrode layer being electrically in contact with the plurality of the nitride semiconductor layers; and

the plurality of the nitride semiconductor layers including a p-type nitride semiconductor layer formed using as nitrogen precursor ammonia together with hydrazine-based material which generates a radical upon thermal decomposition, and the radical being combined with a hydrogen radical to eliminate the hydrogen radical.

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3. The nitride semiconductor light emitting device of claim 2, wherein the electrode layer is made of at least one selected from the group consisting of nickel, gold, silver, chrome, titanium, platinum, palladium, rhodium, iridium, aluminum, tin, ITO, indium, tantalum, copper, cobalt, iron, ruthenium, zirconium, tungsten, lanthanum and molybdenum.

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- 4. The nitride semiconductor light emitting device of claim 2, wherein the plurality of the nitride semiconductor layers includes an n-type nitride semiconductor layer in contact with the electrode layer.
- 5. The nitride semiconductor light emitting device of claim 4, wherein the electrode layer is made of ITO (Indium Tin Oxide).
- 6. The nitride semiconductor light emitting device of claim 2, wherein the p-type nitride semiconductor layer is doped with a dopant and the dopant is magnesium (Mg).
 - 7. The nitride semiconductor light emitting device of claim 2, wherein the p-type nitride semiconductor layer is made of GaN.
 - 8. The nitride semiconductor light emitting device of claim 2, wherein the radical generated upon the thermal decomposition of the hydrazine-based material is CH₃ or NH₂.